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Q. Wang and E. Iwaniczko
National Renewable Energy Laboratory

J. Yang, K. Lord, and S. Guha
United Solar Systems Corporation

K. Wang and D. Han
University of North Carolina at Chapel Hill

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WIDE-GAP THIN FILM SI *n-i-p* SOLAR CELLS DEPOSITED BY HOT-WIRE CVD

Qi Wang,¹ Eugene Iwaniczko,¹ Jeffrey Yang,² Kenneth Lord,² Subhendu Guha,² Keda Wang,³ and Daxing Han³

¹National Renewable Energy Laboratory (NREL) 1617 Cole Blvd., Golden, CO 80401

²United Solar Systems Corp., (USSC) Troy, MI 48084

³Department of Physics and Astronomy, University of North Carolina at Chapel Hill, Chapel Hill, NC 27599

ABSTRACT

High-voltage wide bandgap thin-film Si *n-i-p* solar cells have been made using the hot-wire chemical vapor deposition (HWCVD) technique. The best open-circuit voltage (V_{oc}) has exceeded 0.94 V in solar cells using HWCVD in the entire *n-i-p* structure. A V_{oc} of 0.97V has been achieved using HWCVD in the *n* and *i* layers and plasma-enhanced (PE) CVD for the *p* layer. The high voltages are attributed to the wide-gap *i* layer and an improved *p/i* interface. The wide-gap *i* layer is obtained by using low substrate temperatures and sufficient hydrogen dilution during the growth of the *i* layer to arrive at the amorphous-to-microcrystalline phase transition region. The optical band gap (E_{04}) of the *i* layer is found to be 1.90 eV. These high-voltage cells also exhibit good fill factors exceeding 0.7 with short-circuit-current densities of 8 to 10 mA/cm² on bare stainless steel substrates. We have also carried out photoluminescence (PL) spectroscopy studies and found a correlation between V_{oc} and the PL peak energy position.

INTRODUCTION

Open-circuit voltage (V_{oc}) is the voltage measured between two terminals of a solar cell under illumination at zero current. It roughly measures or relates to the quasi-Fermi energy between electrons and holes of an absorber layer under illumination. Improvements in V_{oc} can certainly benefit the performance of a solar cell if other characteristics are not compromised. Despite major efforts [1-3], fundamental understanding on how to further improve V_{oc} remains a major issue. Experimentally, many research groups have achieved high V_{oc} 's ~1 V by inserting a thin buffer layer between the *p* and *i* layer, such as a wide-gap a-SiC:H or a-SiO:H layer, hydrogen-diluted a-Si:H *i* layer near the amorphous-to-microcrystalline transition, or a wide-gap conductive H-diluted *p* layer, or using a microcrystalline *p* layer [4-7]. In general, the limitation of V_{oc} can be attributed to the bulk *i* layer, doped layers, and interfaces. However, in high V_{oc} cells, it is difficult to separate out effect from each factor, thus making further improvements even more challenging.

For solar cells fabricated by the hot-wire (HW) CVD technique, the reported best initial V_{oc} is 0.92 V in a hybrid devices [8] where the *n* and *i* layers were deposited by HWCVD, and 0.88 V for all-HW solar cells [9] that the *n*, *i*, and *p* layers were entirely made using HWCVD. Many

groups have achieved V_{oc} 's just below 0.90 V for their best HW solar cells [10-12]. The large difference when compared to the PECVD solar cells of 1.05 V motivates us to search for high V_{oc} HW solar cells. When successful, the high deposition rate, which is one of the advantages of HWCVD, can be finally utilized.

In this paper, we present experimental data for high V_{oc} a-Si:H solar cells where at least the *i* layer was deposited using the HWCVD technique. We focus on optimizing the wide-gap *i* layer using H-dilution such that the material is near the phase transition from amorphous-to-microcrystalline silicon at a high deposition rate of 10 Å/s.

EXPERIMENTAL DETAILS

High V_{oc} solar cells were developed in the NREL load-locked two-chamber HWCVD T-system. The details of this system were reported elsewhere [13]. We use a SS/*n-i-p*/ITO configuration in all solar cells, where substrates were bare stainless steel (SS). For all-HW solar cells, a 300-Å *n*-layer was first deposited at 300°C in the dopant chamber. Then an 1800-Å (except for the thickness- dependent study) *i*-layer was deposited under various conditions to search for high V_{oc} . The sample then was transferred back to the dopant chamber for a brief atomic H treatment before depositing an 60-Å buffer layer. Finally, a 140-Å *p*-layer was deposited at 150°C. The solar cell was completed by evaporating 600-Å indium tin oxide (ITO) top contacts, with dot areas of 0.05 cm². For hybrid solar cells, the *n* and *i* layers are deposited at the optimized conditions by HWCVD at NREL, then the unfinished solar cell—sealed in N₂ filled bag—was sent to United Solar for depositing the *p* layer and the top ITO contact. The cell has a total area of 0.26 cm² defined by circular ITO top contact. The evaluation of solar cells was done at NREL and United Solar using standard AM 1.5 condition at 25 °C.

The *i*-layer optimization was performed using the above device configuration. The growth conditions, such as substrate temperature, hydrogen dilution, chamber pressure, and thickness, were varied to search for high V_{oc} solar cells. These conditions were near the threshold of the transition from amorphous-to-microcrystalline silicon. The deposition rate for H-diluted *i* layers is about 10 Å/s. The H-dilution ratio (*R*) of H₂ to SiH₄ is one of the critical parameters that control the phase of the thin film Si.

Photoluminescence was measured on all-HWCVD

solar cells using the 514.5-nm, and 632.8-nm light beams from Ar⁺ and HeNe lasers respectively with power density of 30-100 mW/cm² for the PL excitation. Samples were mounted on a cold stage which provides a temperature range from 80 to 300K. The PL spectra were analyzed using a grating monochromator and detected by a LN₂-cooled Ge detector.

RESULTS AND DISCUSSIONS

Figure 1 shows the effect of hydrogen dilution of *i*-layers on V_{oc} (solid symbols) and FF (open symbols) for all HW solar cells fabricated at NREL. First, we observed that hydrogen dilution increases V_{oc} . For example, V_{oc} has reached over 0.90 V for $R = 1.8$, which is greater than the best V_{oc} of 0.88 V for the solar cell without H-dilution [8]. Symbol * represents the early data for comparison. We also observe that V_{oc} improved by as much as 20 mV with a slight increase of R by 0.45 at $R = 2.25$. Further increases of R cause V_{oc} to decline. We chose $R = 2.25$ as the optimized H-dilution. With increasing R , the *i*-layer has a tendency to become μ c-Si. It is worth noting that the typical V_{oc} of μ c-Si solar cells is less than 0.60 V. All solar cells have good FFs that are greater than 0.70.

Despite having only a few samples, the very sensitive behavior of V_{oc} to R agrees well with the general trend that thin-film Si changes the phase transition from amorphous to microcrystalline silicon with increasing R , which was concluded from the film study [14]. We believe that the wider-gap *i*-layer that is near or on the edge of the phase transition one of the factors leading to the high V_{oc} . The optical bandgap (E_{04}) of the film grown on the glass under the same condition of high V_{oc} solar cells shows a higher value (1.90 eV) than the one (1.88 eV) without H-dilution. The 20-meV increase in E_{04} cannot explain more than 20-mV increases in V_{oc} assuming that the V_{oc} has a linear relationship with bandgap. Other factors must be taken into account such as the effect of the H-diluted *i* layer on the *p* and *i* interface and the *p* layer growth afterward.

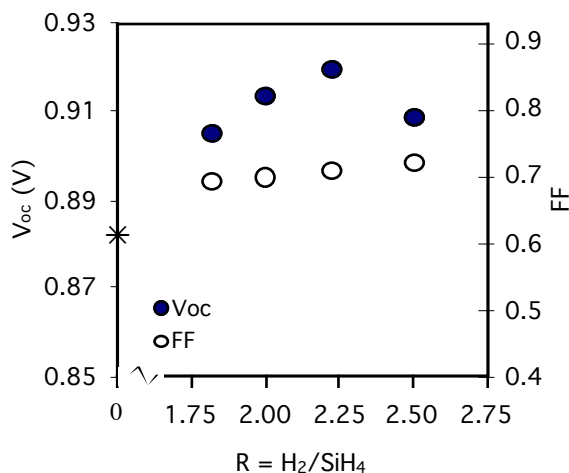


Fig. 1. V_{oc} and FF dependence on the hydrogen dilution of the *i*-layer. The scale of y-axis is magnified.

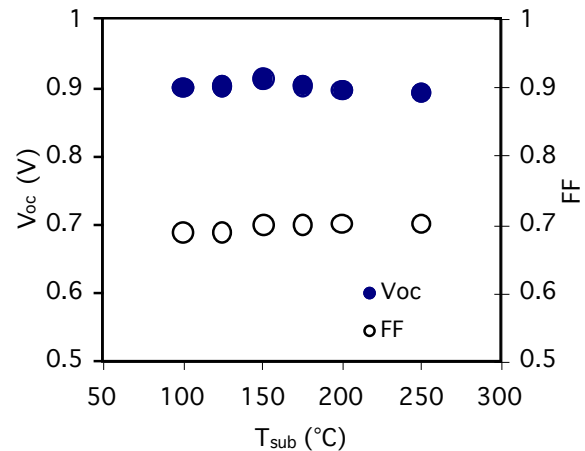


Fig. 2. V_{oc} and FF dependence on the substrate temperature for the solar cells with *i*-layer with H-dilution.

Finally, we concluded that the outcome of increasing V_{oc} using “finite-tuned” H-dilution, which is near the phase transition, is similar for solar cells fabricated by the HWCVD technique or the PECVD method, despite the different growth method and deposition rate.

Figure 2 shows the dependence of solar cell performance on substrate temperature. All HW solar cells have an H-diluted *i* layer with $R = 2.25$, and the temperature changes from 100°C to 250°C. The temperatures used in the figure are the starting temperature and are monitored using two thermocouples (TC) placed inside the chamber. During the deposition, the radiation from the hot-wire heats up the film and substrate. Therefore, the final temperatures, which depend on the deposition time and other factors, are higher than the starting one. Fortunately, most *i* layer depositions are done within 2-3 minutes and the TC reading changes about 20°-30°C. However, the real temperature at the surface of the film is difficult to determine because of the complicated absorption, heat dissipation, type of substrate, and deposition conditions.

We initially grow the H-diluted solar cells at 250°C. The solar cell has a reasonable high V_{oc} of 0.89 V and FF of 0.70. To search for other solar cells with high V_{oc} , we decreased the substrate temperature from 250°C to 100°C. In general, the results suggest that the substrate temperature does not dramatically impact solar cell performance. However, it does cause about 20-mV increase of V_{oc} at 150°C compared to the solar cell at 250°C. Also, at 100°C, we can make a solar cell with V_{oc} slightly higher than 0.90 V. We chose 150°C as the optimized temperature.

To closely examine the effect of *i* layer to the solar cell performance, we selected PL spectra measurements on the same set of solar cells in Figure 2. Most PL signal is believed to come from the *i*-layer, and much less from ITO and thin *p*-layer. Figure 3 shows the correlation between PL peak energy position at 80K and V_{oc} on the same solar cells. In a range of V_{oc} from 0.893 to 0.914 V,

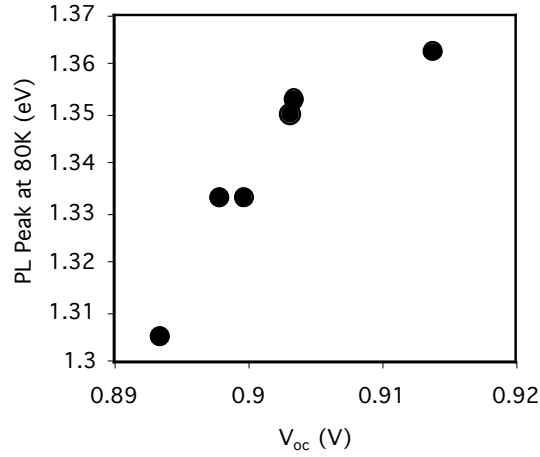


Fig. 3. The PL peak energy position measured at 80K correlated to the V_{oc} for the samples in Figure 2. The higher the V_{oc} , the higher the peak-energy position.

the PL peak energy position increases with V_{oc} and is independent of the substrate temperature (see Fig. 2). At low temperatures such as 80K, PL measured the radiative recombination energy of excited electron-hole pairs. In a-Si:H materials, the peak energy position relates to the optical gap and the width of band tails. Deconvoluting the PL data to the bandgap and/or band-tail width is not the subject of this paper. The correlation of PL peak energy position with V_{oc} suggests that V_{oc} increases qualitatively with increase of the bandgap of the i layer. However, the non-linear relationship between PL peak energy and V_{oc} at higher V_{oc} weakens the argument.

Figure 4 shows the effect of the i -layer thickness on solar cell performance. The i -layer was grown at the condition that was optimized for hydrogen dilution with $R=2.25$ at 150°C . The three solar cells were completed at NREL. This experiment is to test the thickness dependence of $\mu\text{-Si}$ growth that was reported by United Solar [15] in the solar cell. We found that V_{oc} and FF decrease with increasing thickness. Interestingly, the V_{oc} for a solar cell just over $1\ \mu\text{m}$ thick is still quite good (0.88 V), although the FF decreased dramatically. These HW results agree with the previous report PECVD solar cells by United Solar.

In all-HW n - i - p solar cell fabricated at NREL, a 60-Å higher H-diluted amorphous silicon layer was inserted between the i and p layers and was found to help the solar cell performance [8]. We also used the same buffer layer and the same p layer that were reported previously [9] for all the high V_{oc} solar cells at NREL.

Table I summarizes the optimized high- V_{oc} solar cells growth condition and performance. The first data show the i -layer deposition parameters. For the all-HW n - i - p solar cells, the best initial high-voltage solar cell has a V_{oc} of 0.941 V, with FF of 0.749, J_{sc} of $8.2\ \text{mA}/\text{cm}^2$, and efficiency (Eff.) of 5.8%. High V_{oc} solar cells, in general, are designed for the wide-gap top cell in the multijunction structure. Therefore, the i -layer is thin (1800 Å) and the

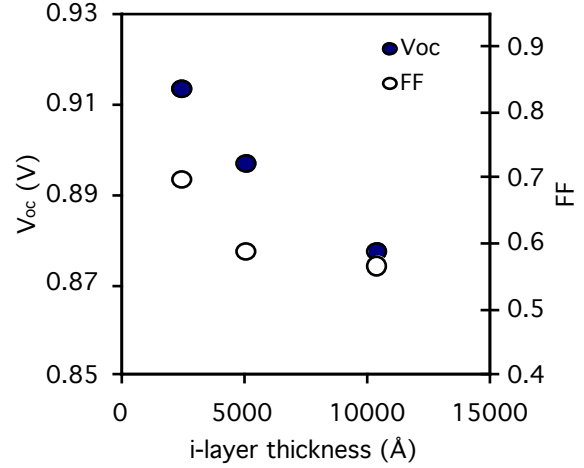


Fig. 4. V_{oc} and FF dependence on the thickness of i -layer at the optimized condition of H-dilution.

short-circuit current density is low. To achieve high efficiency for this type of cell, we increase the i -layer thickness such that the efficiency is optimized. The best initial-efficiency solar cell has a V_{oc} of 0.931 V, FF of 0.708, J_{sc} of $10.9\ \text{mA}/\text{cm}^2$, and Eff. of 7.2% optimized at 2500 Å. The stability test of those solar cells is under way. However, we do have light-soaking data on a solar cell with the i -layer grown close to the best high- V_{oc} solar cell. This cell shows a degradation of V_{oc} from 0.898 to 0.861 V.

Table 1. Summary of High- V_{oc} Solar Cells.

High- V_{oc} solar cell optimized i -layer process parameters

| | SiH ₄ (sccm) | H ₂ (sccm) | P (mTorr) | T _{sub} (°C) |
|------------|----------------------------|--------------------------|--------------|-----------------------|
| i -layer | 45 | 100 | 18 | 150 |

High- V_{oc} all-HW solar cell performance

| | V_{oc} (V) | FF | J_{sc} (mA/cm ²) | Eff. (%) |
|-----------------------|--------------|-------|-----------------------------------|-------------|
| Best Initial V_{oc} | 0.941 | 0.749 | 8.2 | 5.8 |
| Best Initial Eff. | 0.931 | 0.708 | 10.9 | 7.2 |

Light-soaking results from similar i -layer to high- V_{oc} cell

| | | | | |
|-----------------|-------|-------|-------|-----|
| Initial | 0.898 | 0.661 | 10.31 | 6.1 |
| After 1000 hour | 0.861 | 0.591 | 9.65 | 4.9 |

High- V_{oc} NREL-USSC hybrid solar cell performance

| | V_{oc} (V) | FF | J_{sc} (mA/cm ²) | Eff. (%) |
|-----------------------|--------------|-------|-----------------------------------|-------------|
| Best Initial V_{oc} | 0.971 | 0.717 | 9.63 | 6.70 |
| Best Initial Eff. | 0.962 | 0.716 | 10.12 | 6.97 |

The last data show the performance on the collaborated solar cells between NREL and United Solar. Using the same *i*-layer that was optimized for HW high-Voc solar cells, the best initial high voltage solar cell has V_{oc} of 0.971 V, with FF of 0.717, J_{sc} of 9.63 mA/cm², and Eff. of 6.70%. And the best initial efficiency solar cell has a V_{oc} of 0.962 V, FF of 0.716, J_{sc} of 10.12 mA/cm², and Eff. of 6.97%.

CONCLUSIONS

In summary, high-performance, high V_{oc} (0.941 V in all-HW and 0.971 V in hybrid) a-Si:H solar cells have been fabricated. These values are the best results to date of V_{oc} using the HWCVD technique. The V_{oc} improvement was achieved by incorporating materials grown with H-dilution close to the phase transition from amorphous to microcrystalline silicon in the *i*-layer. The V_{oc} is sensitive to the hydrogen dilution near the optimized condition. We also found that a low substrate temperature of 150°C for the *i*-layer was also essential. We believe that the wide-gap *i*-layer is the key for improving of V_{oc} . Increasing *i*-layer thickness from 1800 to 10,000 Å at the optimized $R = 2.25$ causes V_{oc} to decrease.

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